

ESSCIRC/ESSDERC 2023
SiNANO-ICOS Workshop

“European Strengths and Gaps in Emerging Semiconductor Technologies”

Advanced computation: review of main EU and international activities and technologies

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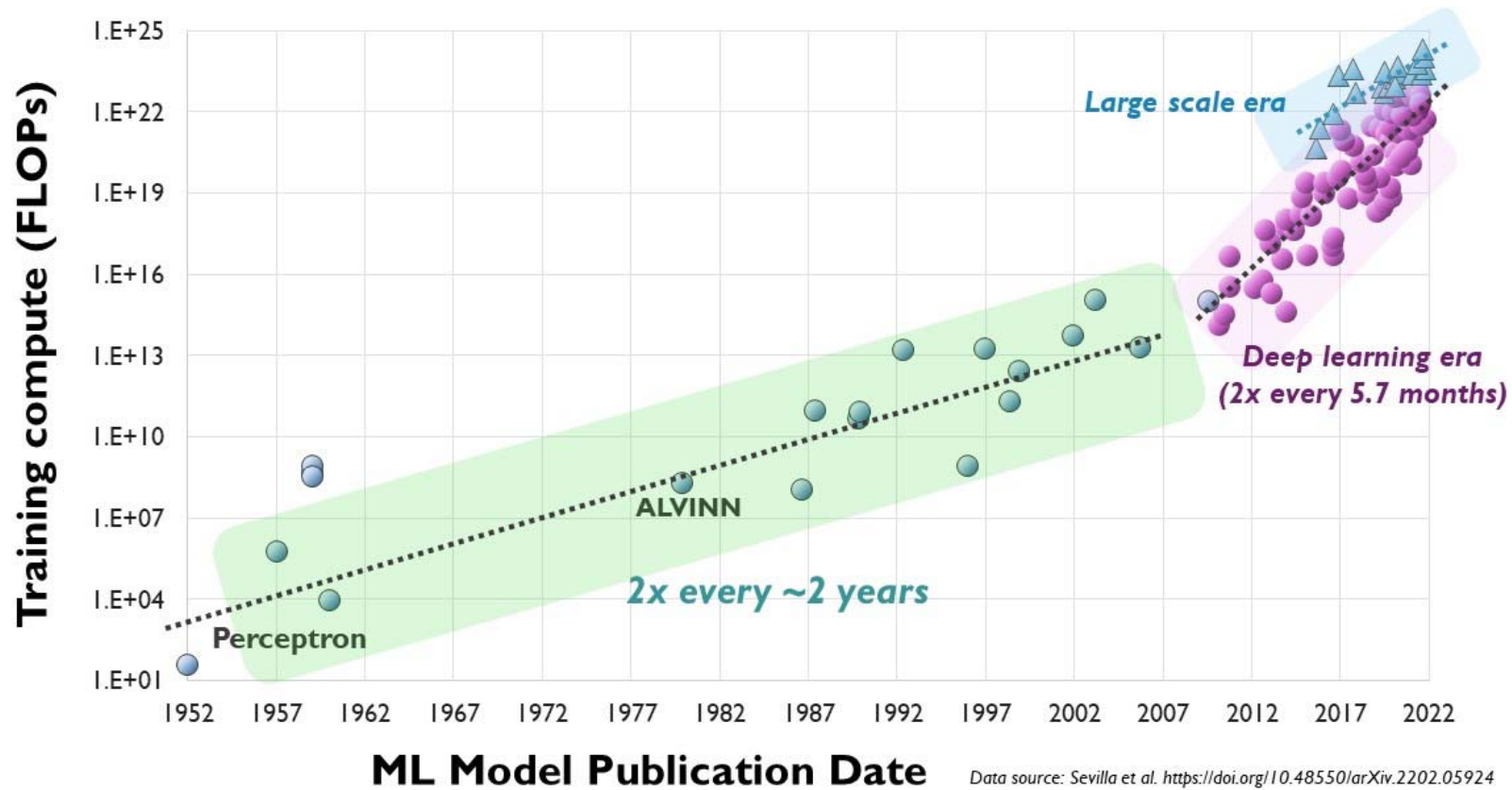
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Lisbon, September 11, 2023

Outline

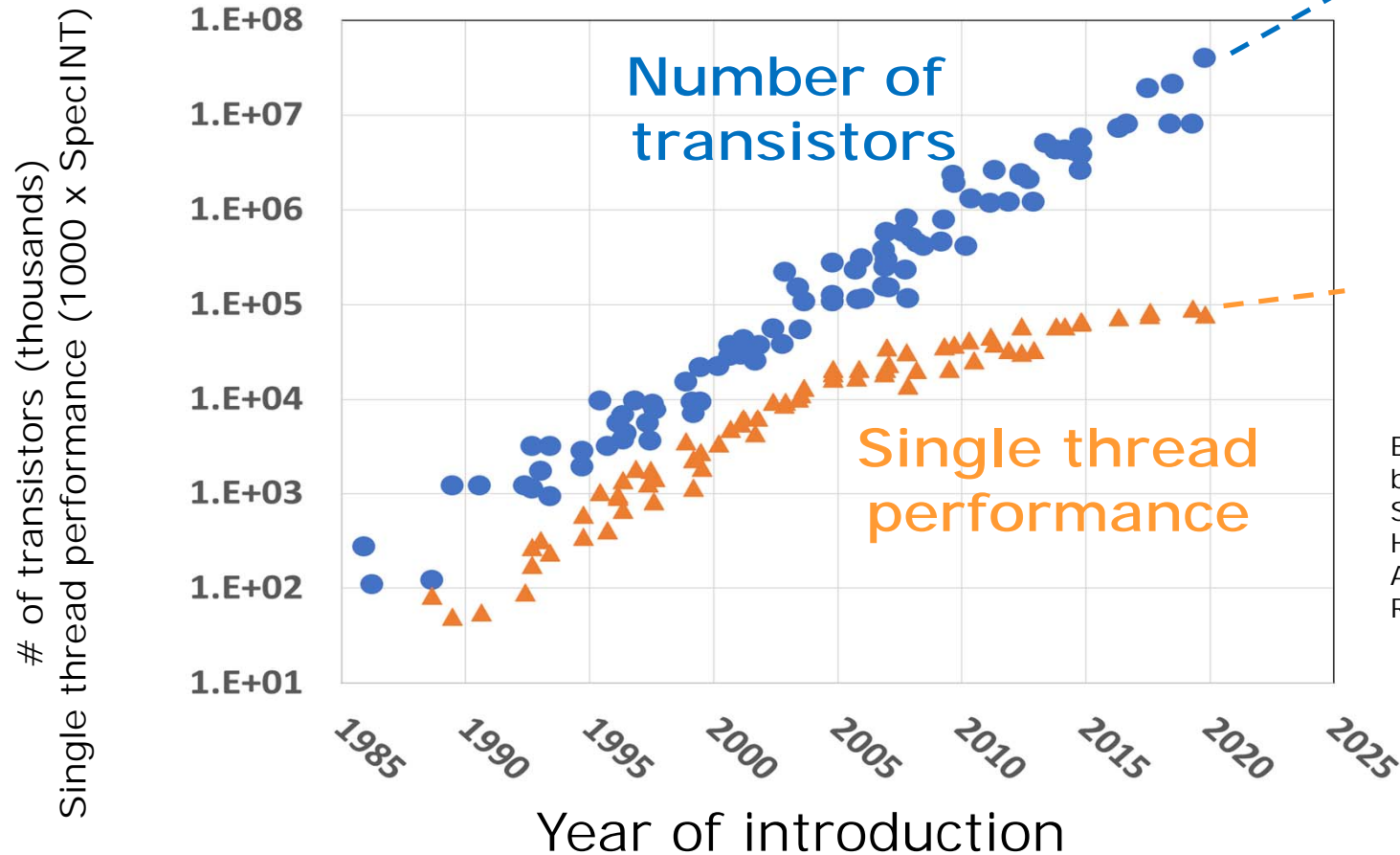
- Introduction: trends and challenges
 - Computing roadmap:
 - CMOS device architecture
 - 2D materials for FEOL
 - New materials for BEOL
 - Lithography
 - Memory technologies
 - Beyond Von Neumann disruptive approaches:
 - Near or in-memory computing
 - Quantum computing
 - Heterogenous integration: from chiplets to functional backside
 - EU and non-EU actors
 - Conclusions
-

Compute needs for ML continue to grow



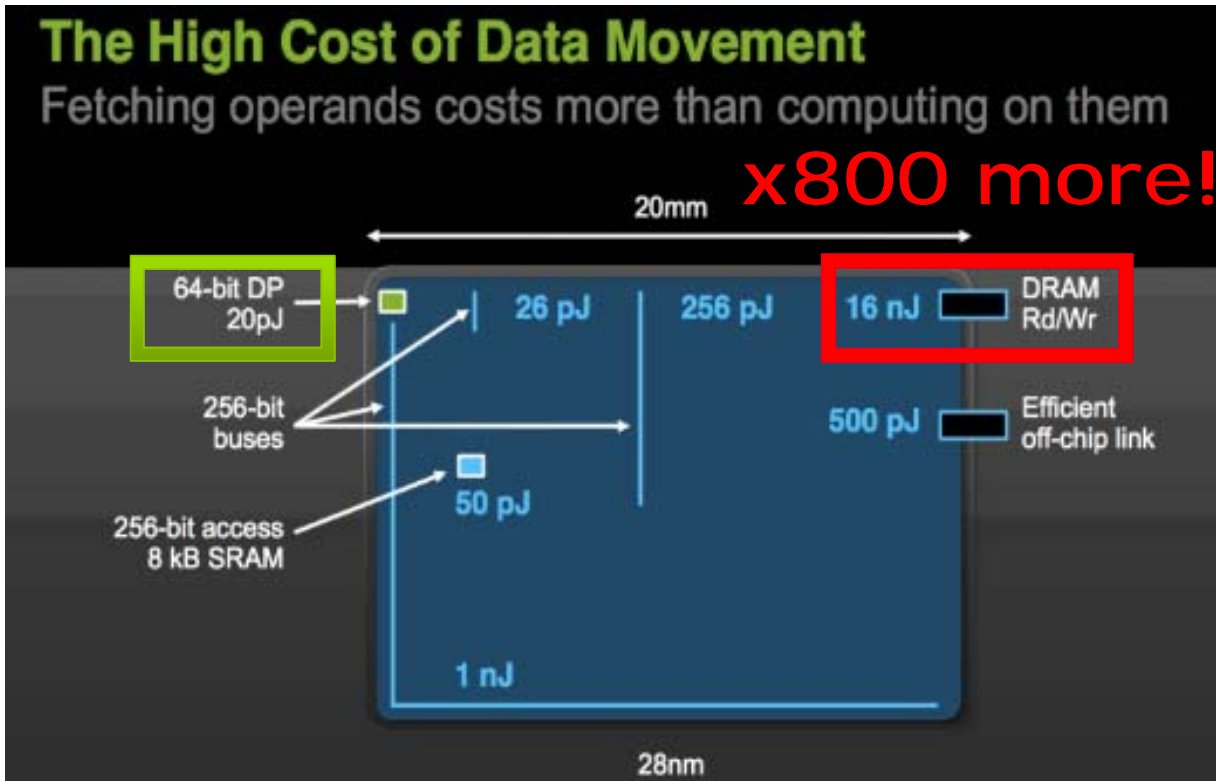
ML=machine learning

Slowdown of Single Thread Performance in CPUs



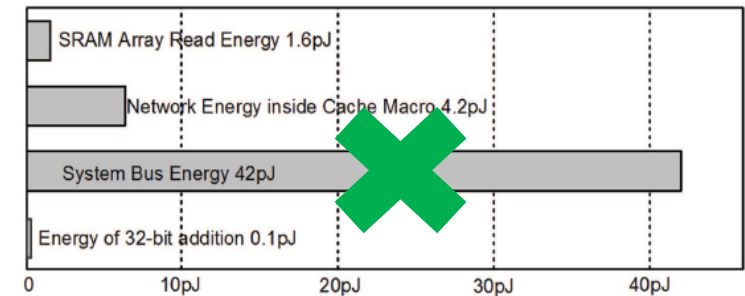
Based on original data plotted by M. Horowitz, F. Labonte, O. Shachan, K. Olukotun, L. Hammond, C. Batten. Additional data compiled by K. Rupp

The cost of moving data



Bill Dally, "To ExaScale and Beyond", 2010

[J. Wang – ISSCC'19]

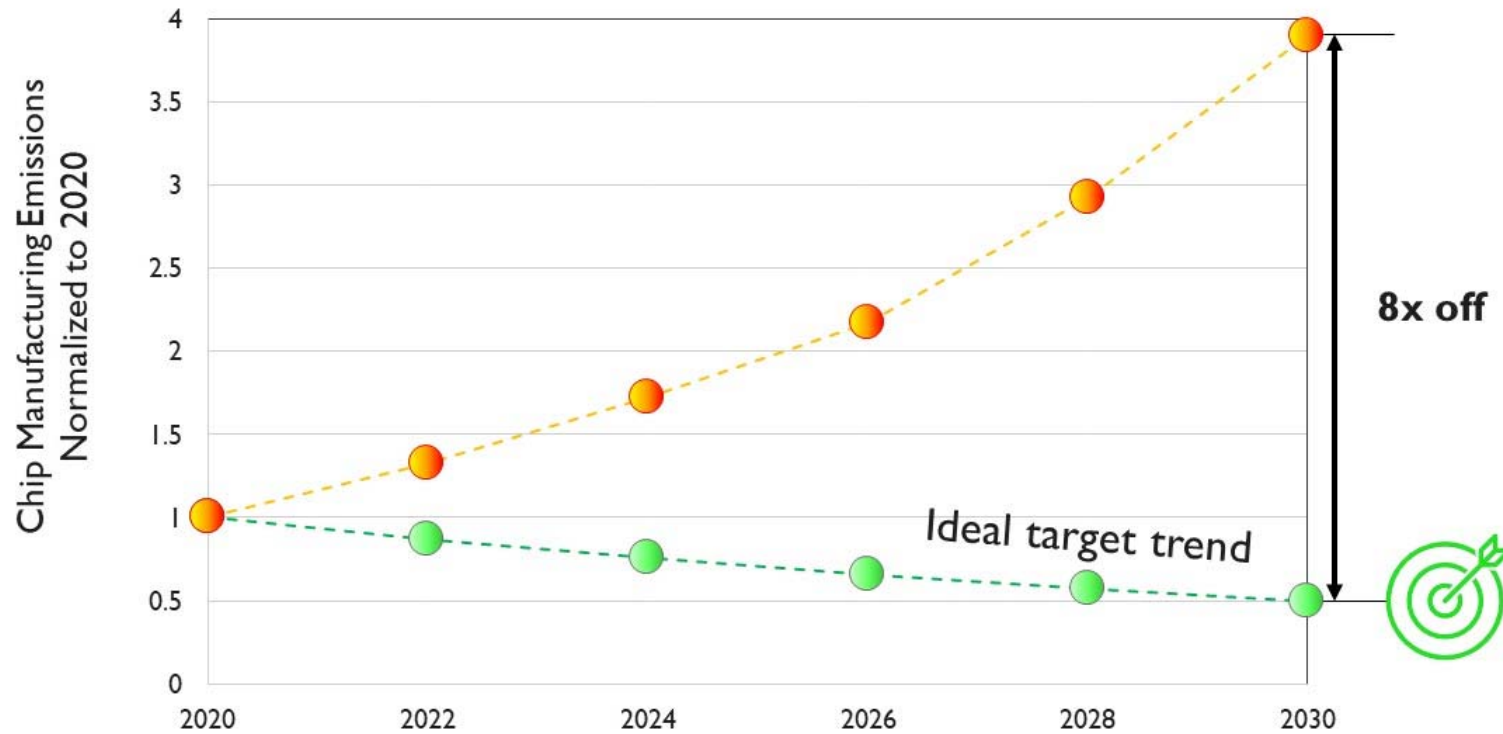


~90% of energy is in data transfer
→ IMC could lead 8x reduction

Operation energy is negligible

Memory access and control energies dominate

Carbon Emissions Estimate of Logic Manufacturing: “Do Nothing” Scenario



Constant electricity mix (0.49 kCO₂eq/kWh), Abatement and GHG global warming potential according to IPCC assumed for the years 2020-2030. Volume technology mix from IBS “Foundry Market Trends and Strategic Implications” Vol 30, N 12, Dec 2021. Logic nodes only. *imec.netzero emissions estimate of imec process nodes representative of foundry nodes.

The required gain in energy efficiency

> 1000x
by
2030

CMOS scaling

Memory technologies

Disruptive Computing

Chiplet & 3D System

New device architectures to extend scaling

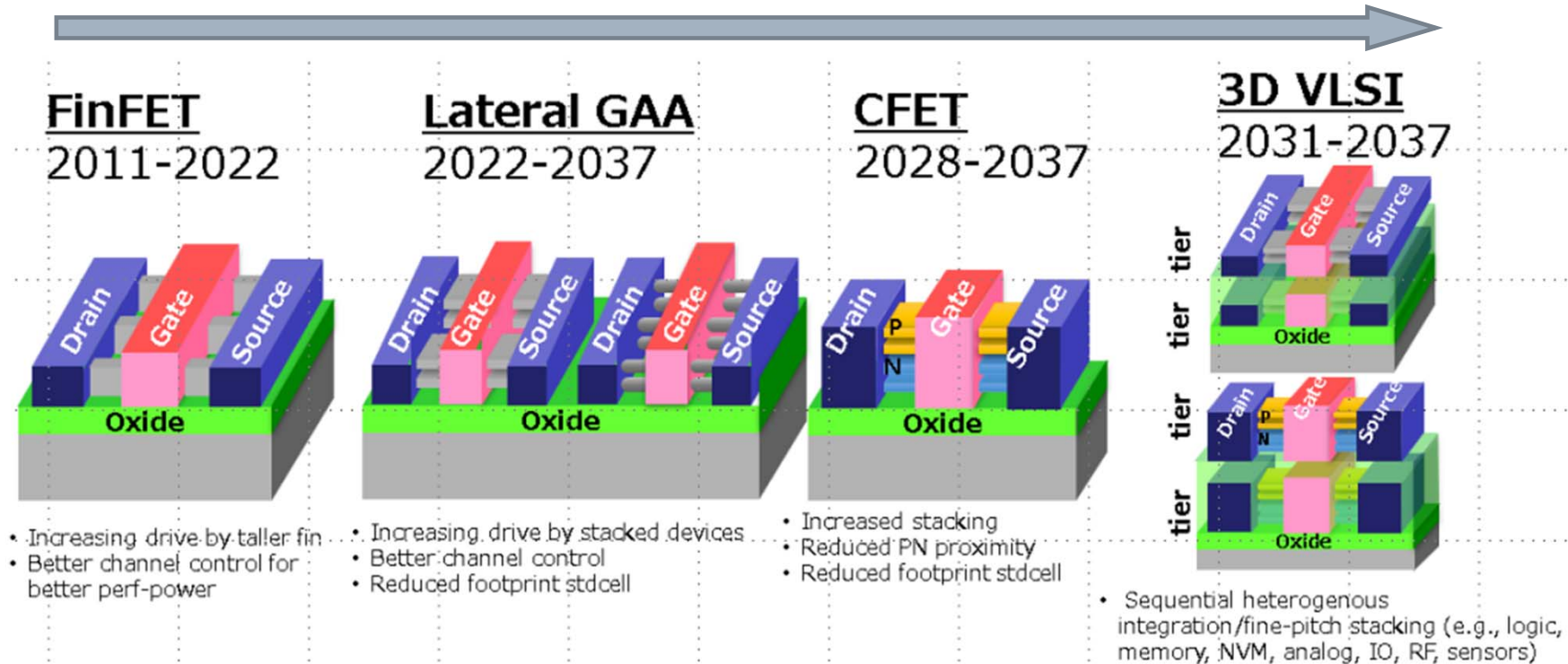
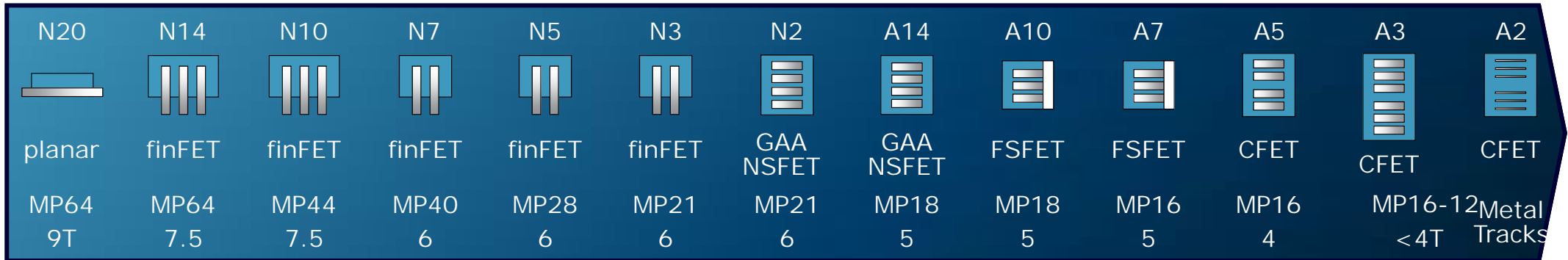


Figure MM-4 Evolution of device architectures in the IRDS More Moore roadmap

Source: 2023 IRDS Roadmap

Logic scaling roadmap



Std cell SDB SAGC FS wall VHV? Common Gate?

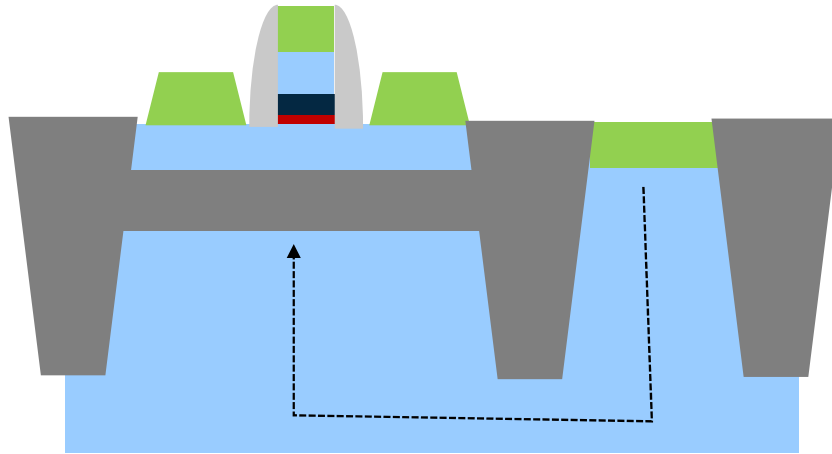
Backside BS-PDN BPR BS Interconnect BS PS

BEOL Ru DME Ru SemiD +AG AR6 Uber via/
New alloy Act. Interc

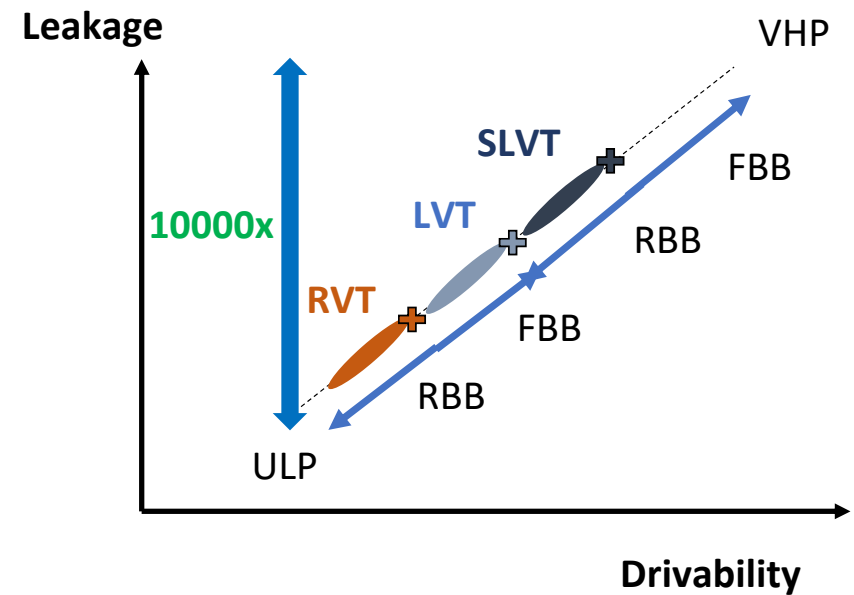
CMOS 2.0 AuC

NS=nanosheet
 FS=forksheets
 CFET=complementary FET
 MP=metal pitch
 BS=backside
 AUC=array under CMOS

FD-SOI Technology

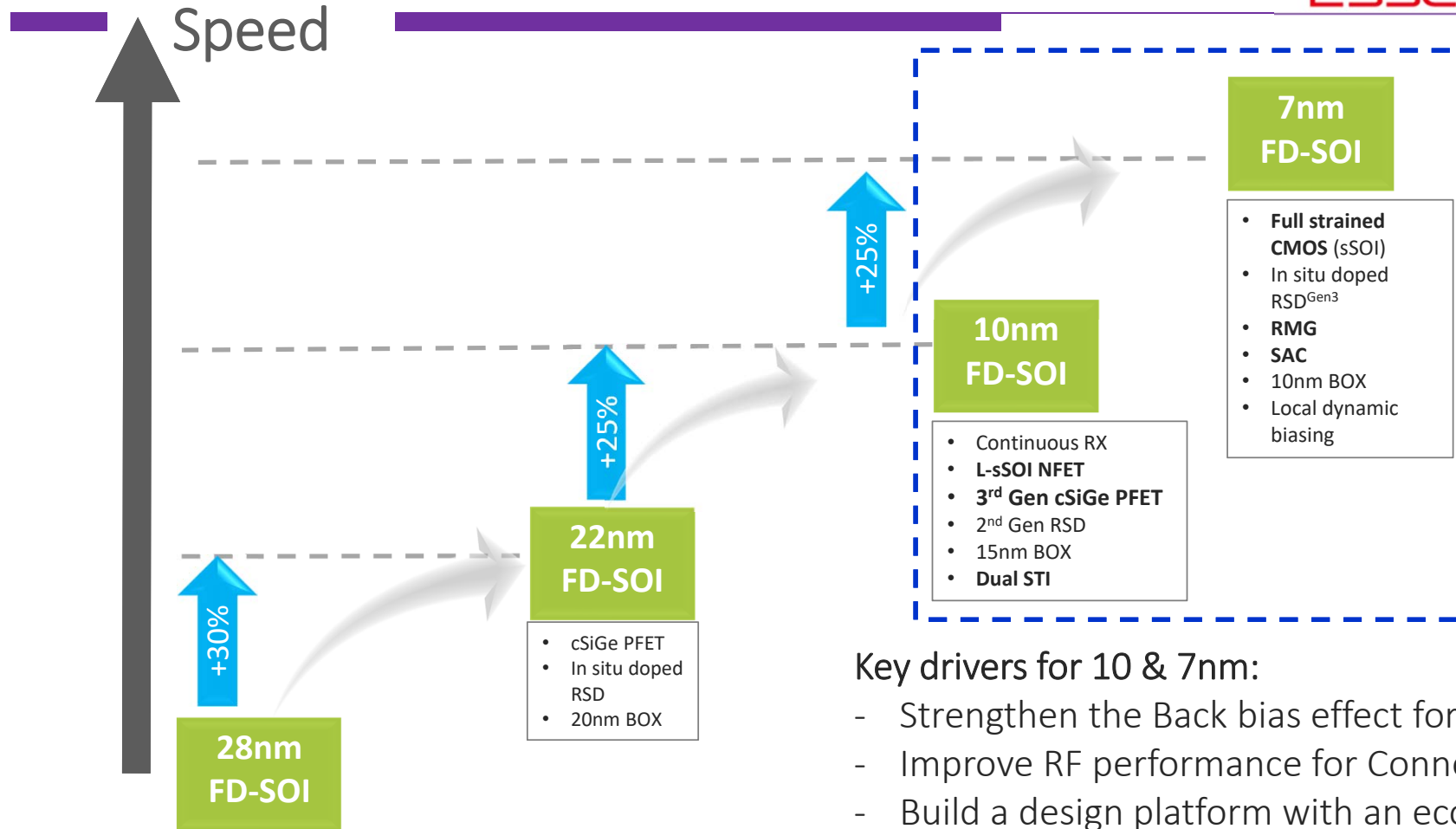


	22FDX	14nm FinFET	28nm Bulk	45nm PDSOI
f_T n-FET [GHz]	347	314	310	296
f_{max} n-FET [GHz]	371	180	161	342
f_T p-FET [GHz]	242 275 (mmWave)	285	185	-
f_{max} p-FET [GHz]	288 299 (mmWave)	140	104	-



RBB: Reverse Body Bias
 FBB: Forward Body Bias
 ULP: Ultra-Low Power
 VHP: Very High Performance

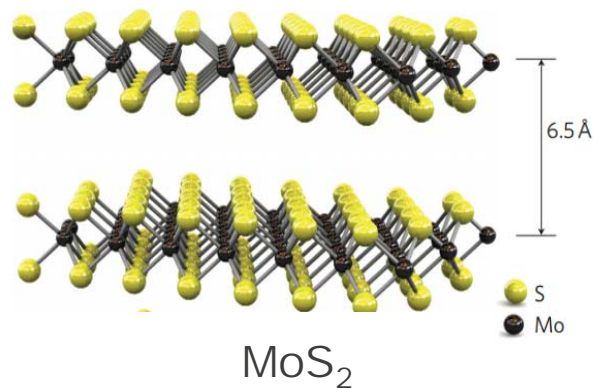
FD-SOI Roadmap



Key drivers for 10 & 7nm:

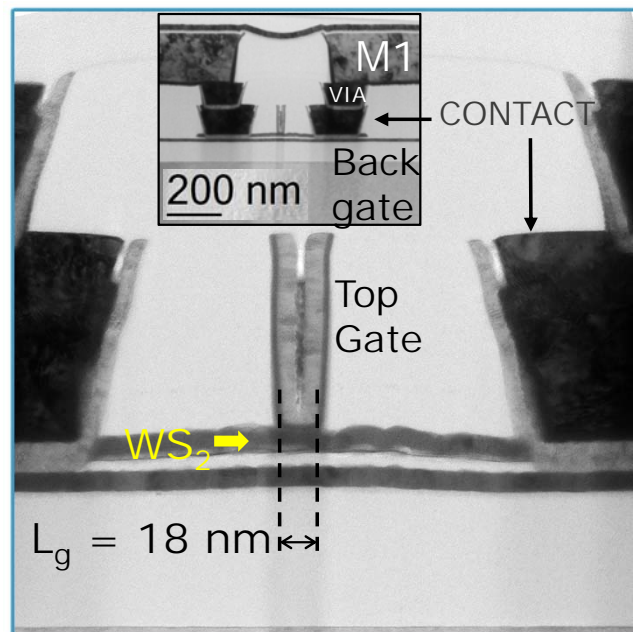
- Strengthen the Back bias effect for Energy saving
- Improve RF performance for Connectivity
- Build a design platform with an ecosystem

2D Atomic Channels: Next generation logic devices



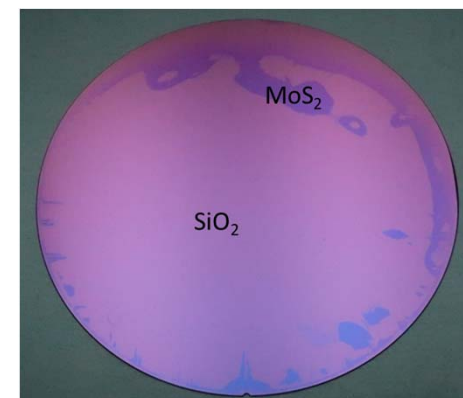
Monolayer channel thickness enables gate length scaling while keeping high performance

300mm Flow



I. Asselberghs et al, IEDM 2020

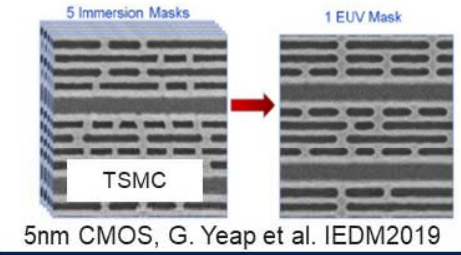
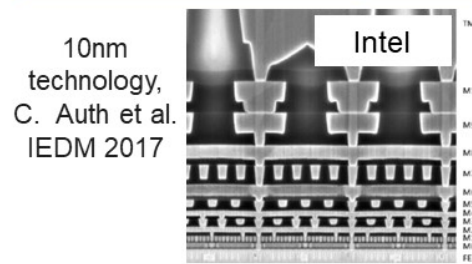
Layer Transfer:



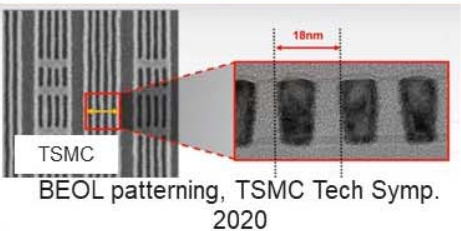
CEA-Leti, un-published

Industry BEOL trends

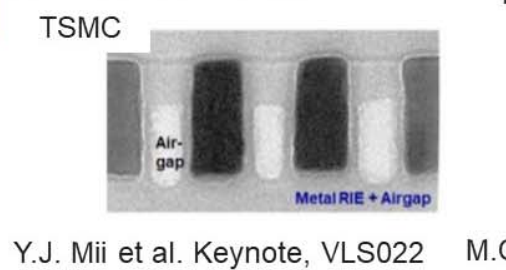
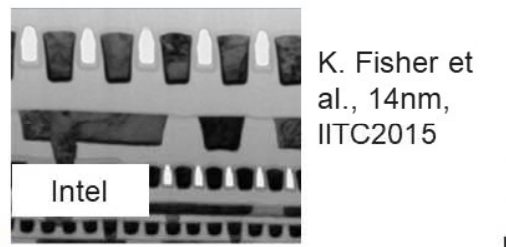
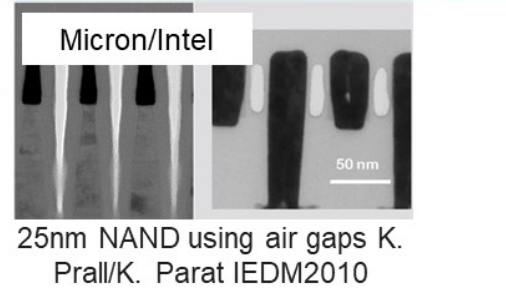
~36-40nm BEOL pitch



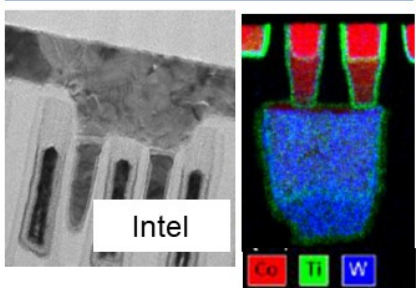
<20nm pitch



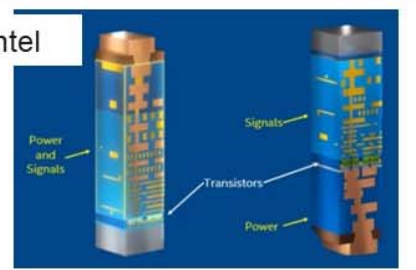
AGs in memory & logic



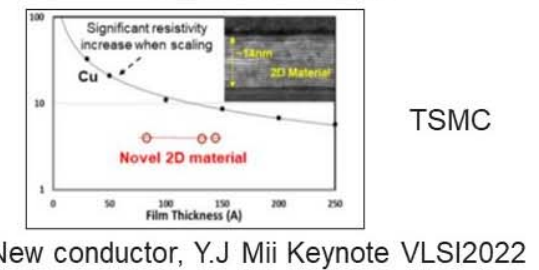
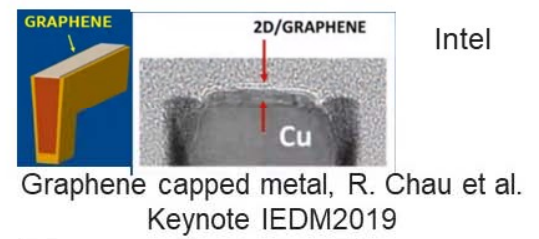
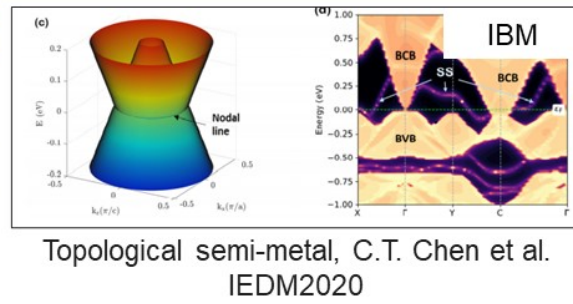
Co interconnects



Backside Power Delivery



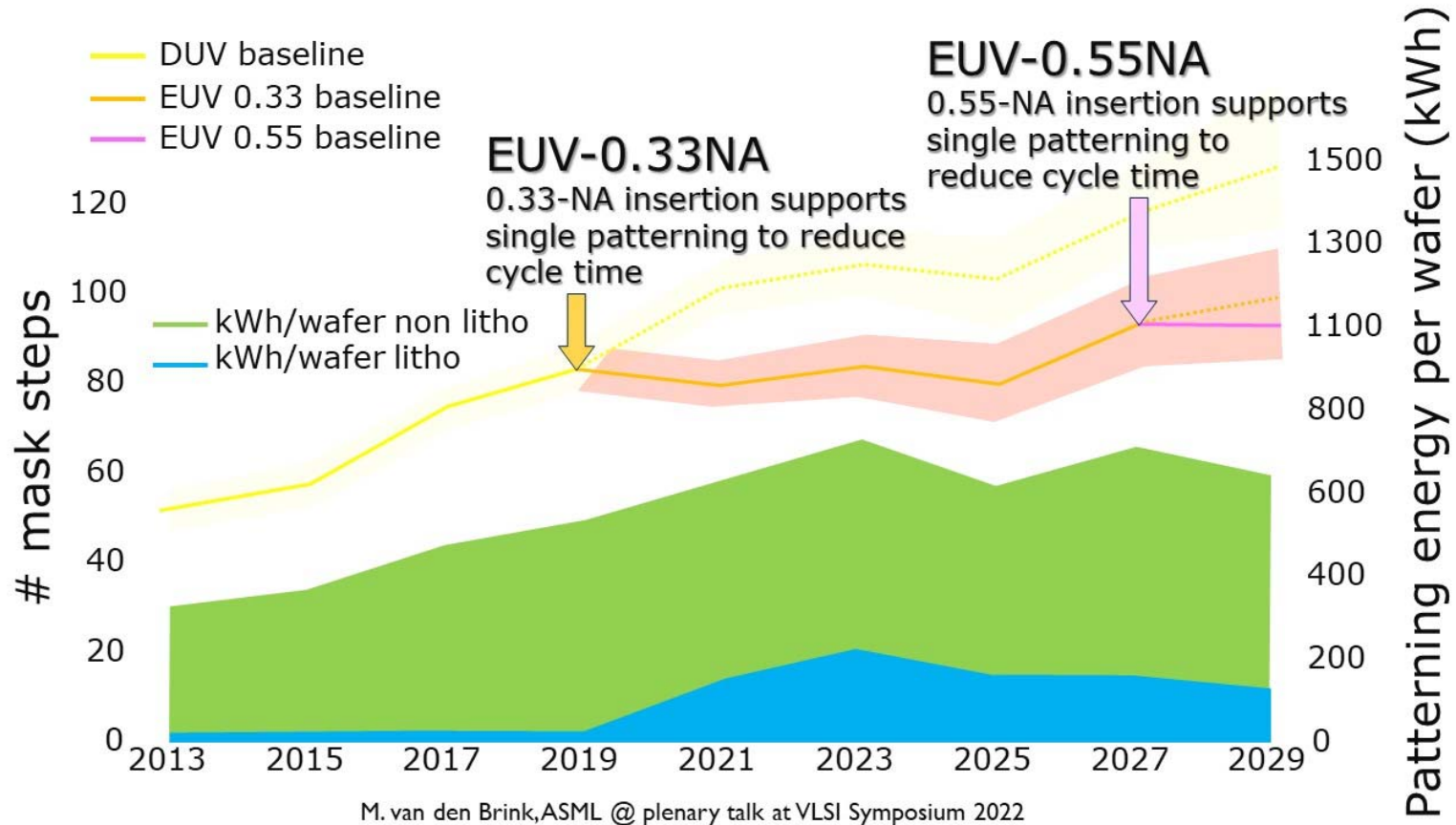
New materials on the horizon



Pitch scaling, airgaps both in memory and logic, new materials

Courtesy: Zsolt Tokei (imec)

EUV lithography key enabler for scaling



Emerging Non-Volatile Memories

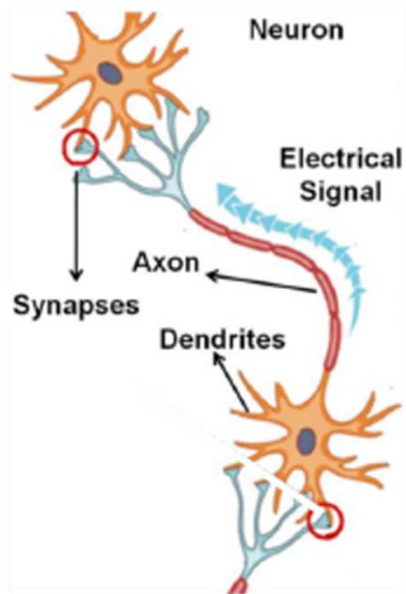


	NOR FLASH	MRAM	PCRAM	OxRAM	FeRAM (PZT)	FeRAM (HfO ₂)
Programming power	~200pJ/bit	~20pJ/bit	~300pJ/bit	~100pJ/bit	~10fJ/bit	~10fJ/bit
Write speed	20 μs	20 ns	10-100 ns	10-100 ns	<100ns	14ns @ 2.5V (SONY) 4ns @ 4.8V (LETI)
Endurance	10 ⁵ - 10 ⁶	10⁶-10¹⁵	10 ⁸	10 ⁵ – 10 ⁶ on 16 kbit	> 10¹⁵	> 10¹¹ single device 10⁶ – 10⁷ on 16 kbit
Retention	> 125°C	85°C - 165 °C	165°C	> 150°C	125°C	125°C
Extra masks	Very high (>10)	Limited (3-5)	Limited (3-5)	Low (2)	Low (2)	Low (2)
Process flow	Complex	Medium	Medium	Simple	Simple	Simple
Multi-Level Cell	Yes	No	Yes	Yes	No	No
Scalability	Bad	Medium	High	High	Medium	Poor (2D) High (3D)

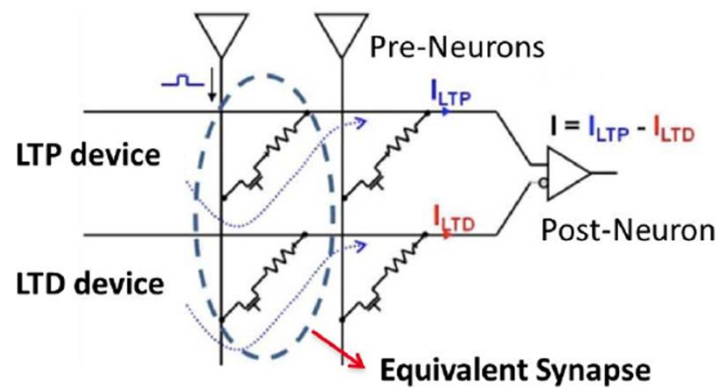
Memory activity focus on embedded NVM for NOR flash replacement

Neuromorphic based RRAM circuit

M. Suri et al, IEDM 2011.



2 PCRAM Example:



PCM

GST
GeTe
GST + HfO₂

CBRAM

Ag / GeS₂

OxRAM

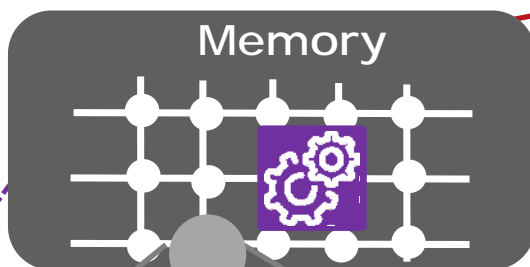
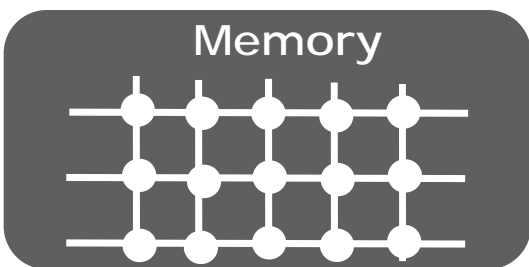
TiN/HfO₂/Ti/TiN

FeRAM

In memory computing

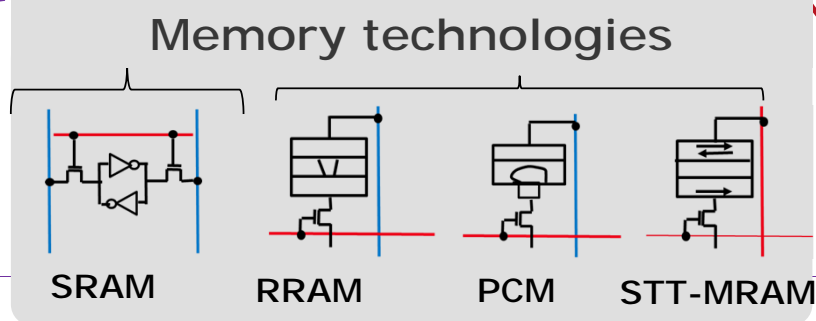
Von Neumann computing

In-memory computing

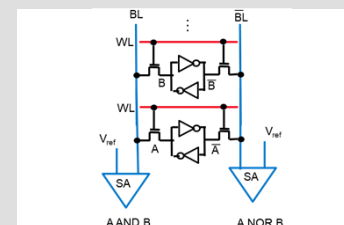


input-data D

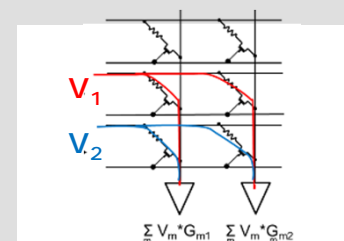
results $f(D)$



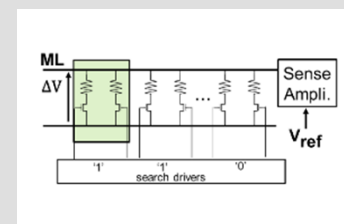
Logic and arithmetic operations



Digital operations using SRAM

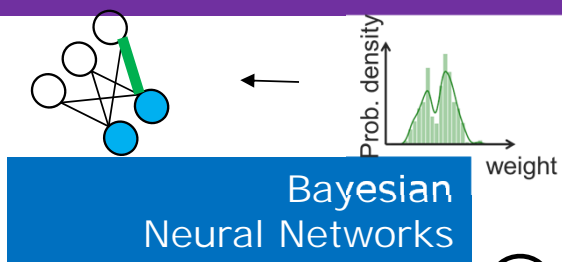


Analog: multiply and accumulate

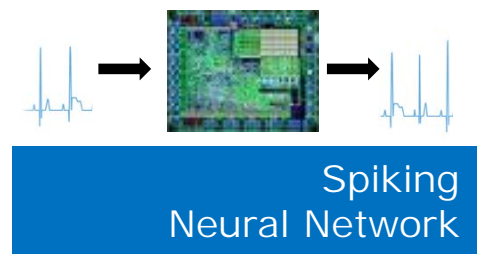
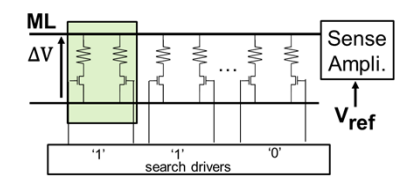


Searching / matching (CAM)

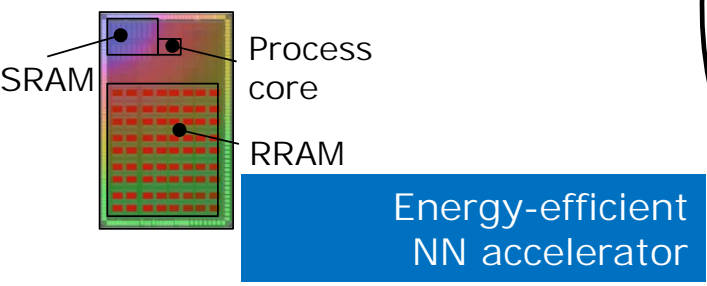
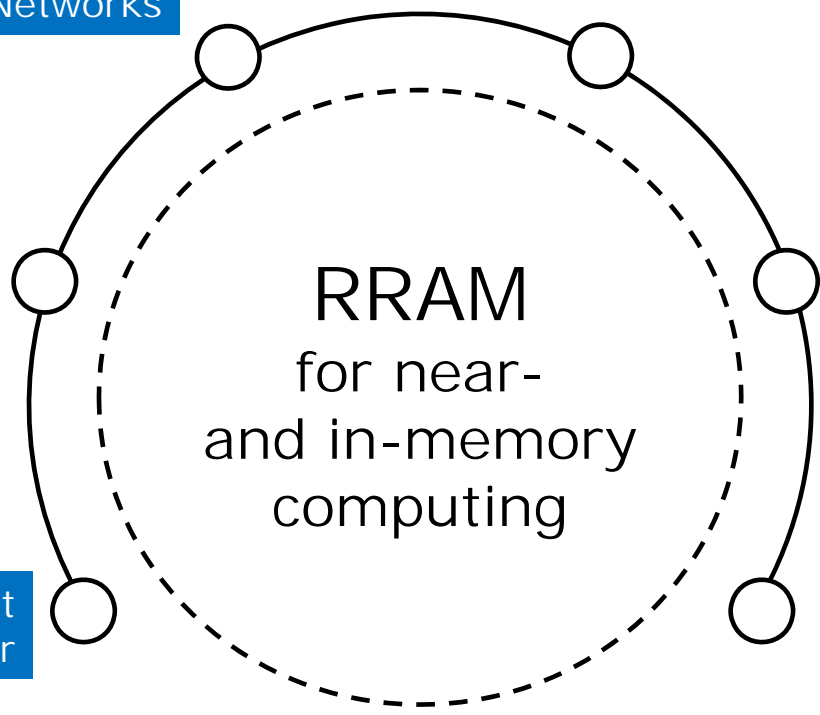
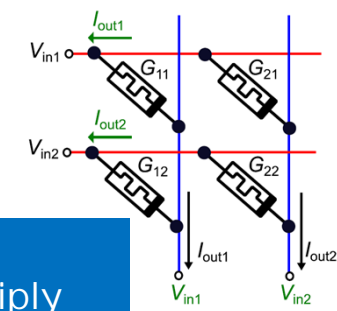
Near- & in-memory computing



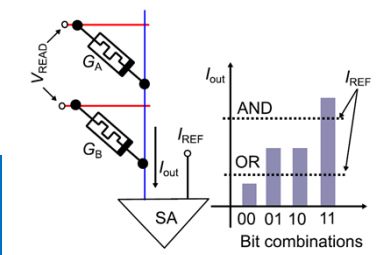
Search/match operations (CAM)



Deep learning, matrix-vector multiply

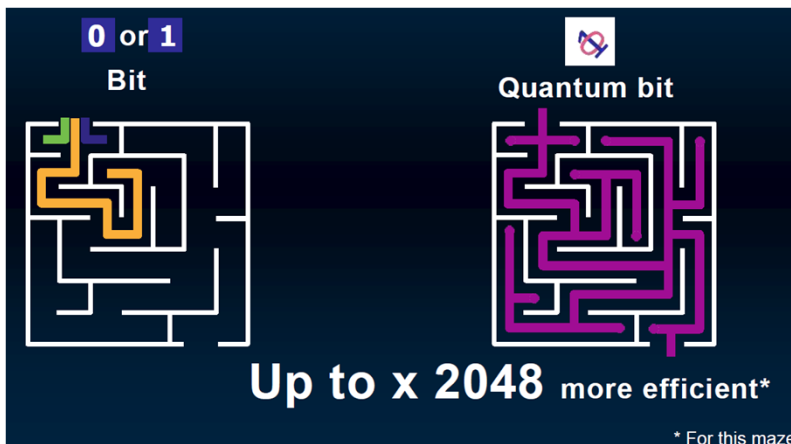
$$\begin{bmatrix} A_{11} & A_{12} \\ A_{21} & A_{22} \end{bmatrix} \begin{bmatrix} x_1 \\ x_2 \end{bmatrix} = \begin{bmatrix} b_1 \\ b_2 \end{bmatrix}$$


In-memory logic



From bits to q-bits

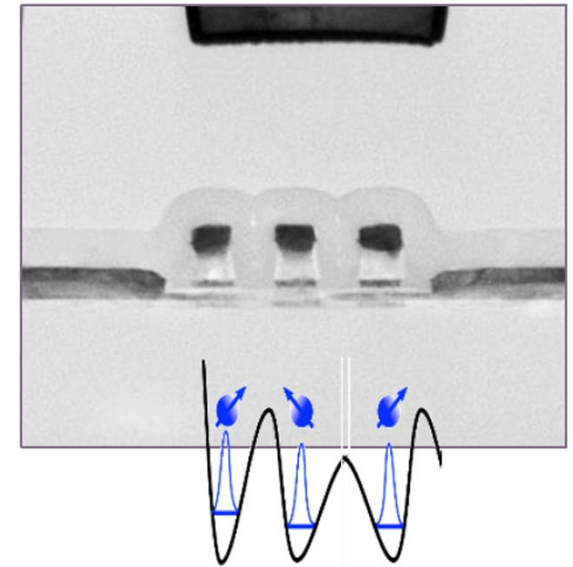
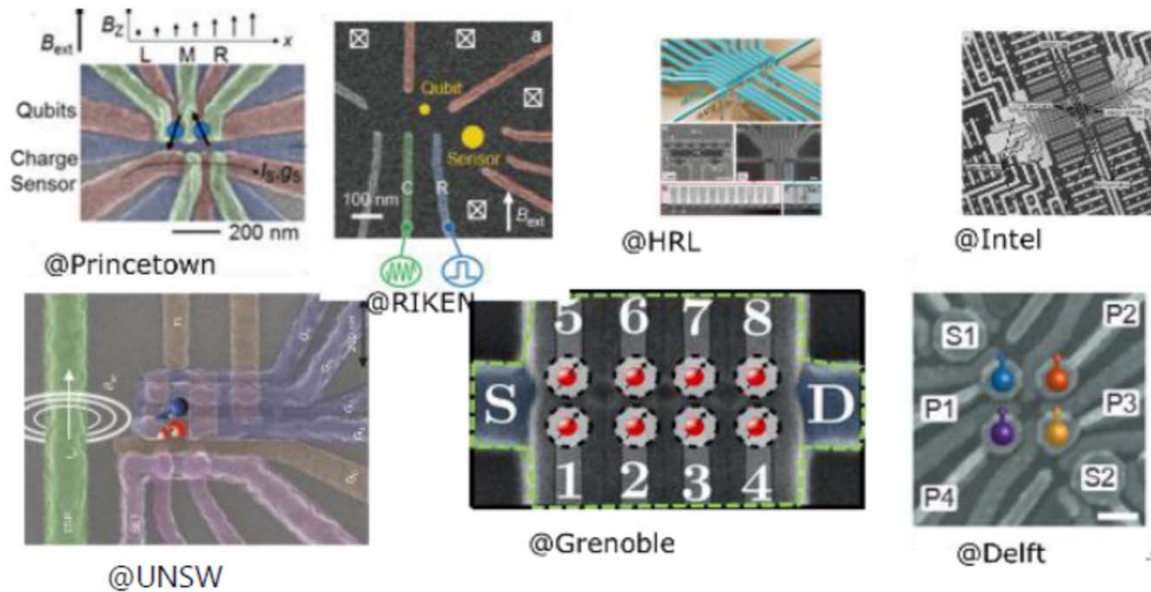
Quantum Physics to compute



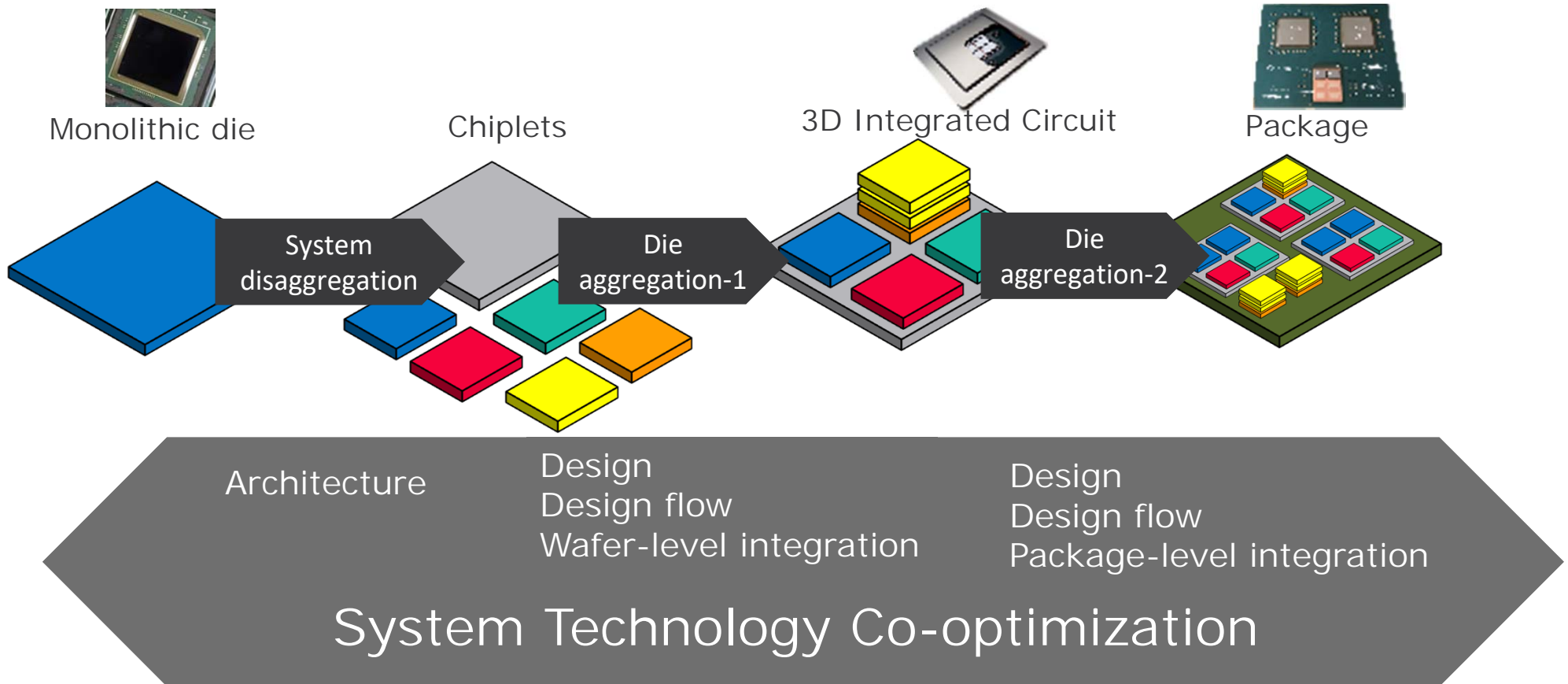
	Superconductor	Si spin qubit	Trapped ion	Photon
Size*	(100 μ m) ²	(100nm) ²	(1mm) ²	~(100 μ m) ²
1qubit fidelity	99.96%	99.93%	99.98%	
2qubit fidelity	~99.3%	>99%	99.9%	50% (measurement) 98% (gates)
Speed**	12-400 ns	~1 μ s	100 μ s	1 ms
Variability	3%	0.1%-0.5%	0.01%	0.5%
T° of operation	15mK	1K	10K	4K/10K
Entangled qubits	433 (IBM)	3 (TU) (6 - QuTech)	32 (IonQ)	70 (Pan-China)

From bits to q-bits

- Quantum Physics to compute

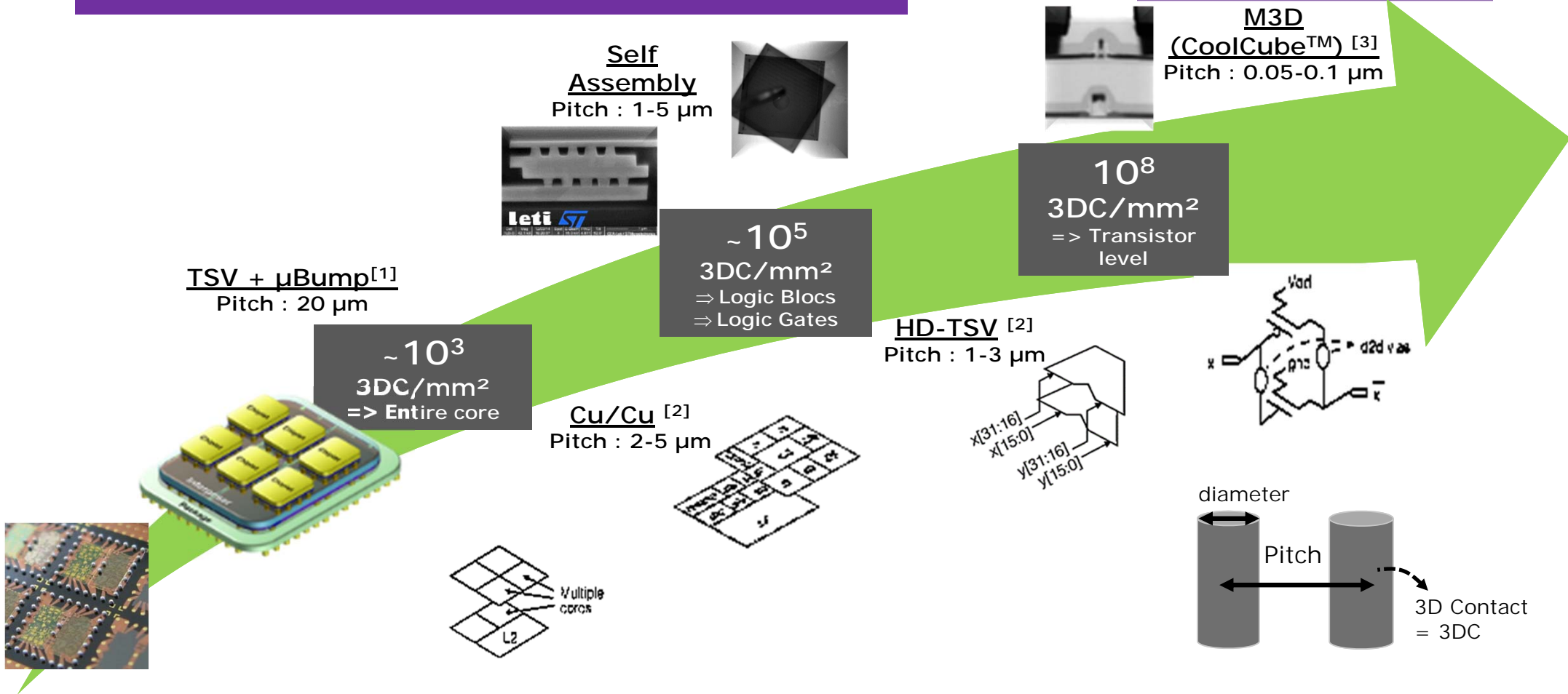


Chipllets: the new IC design paradigm



Up to 100x gain on Power Efficiency with 3D

3D: from packaging to monolithic



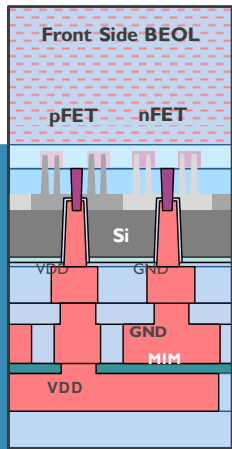
[1] Cheramy, S., et al. "Advanced Silicon Interposer", C2MI Workshop, 2015

[2] Patti, B., "Implementing 2.5D and 3D Devices", In AIDA workshop in Roma, 2013

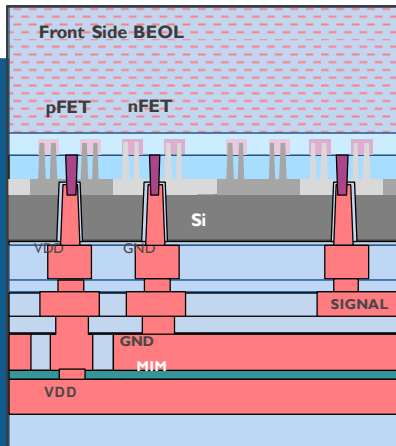
[3] Batude, P., et al. "3DVLSI with CoolCube process: An alternative path to scaling ." VLSI technology symposium 2015

Towards a functional backside

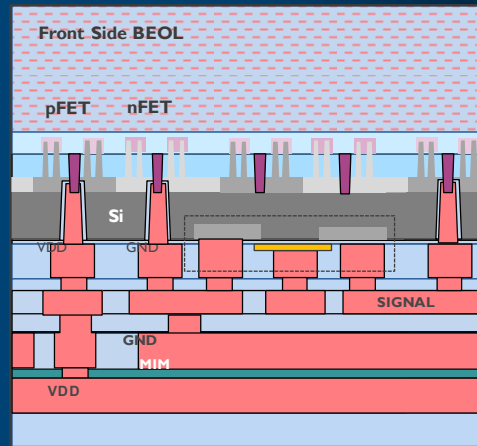
Backside Power Delivery



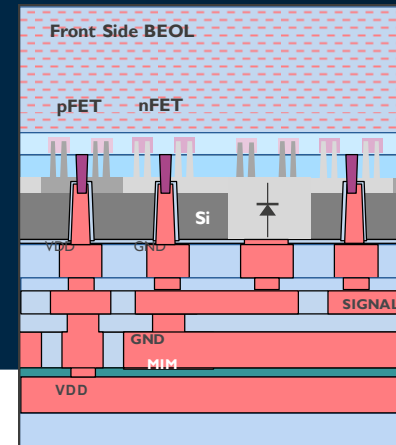
Backside Global Interconnect



Backside Devices



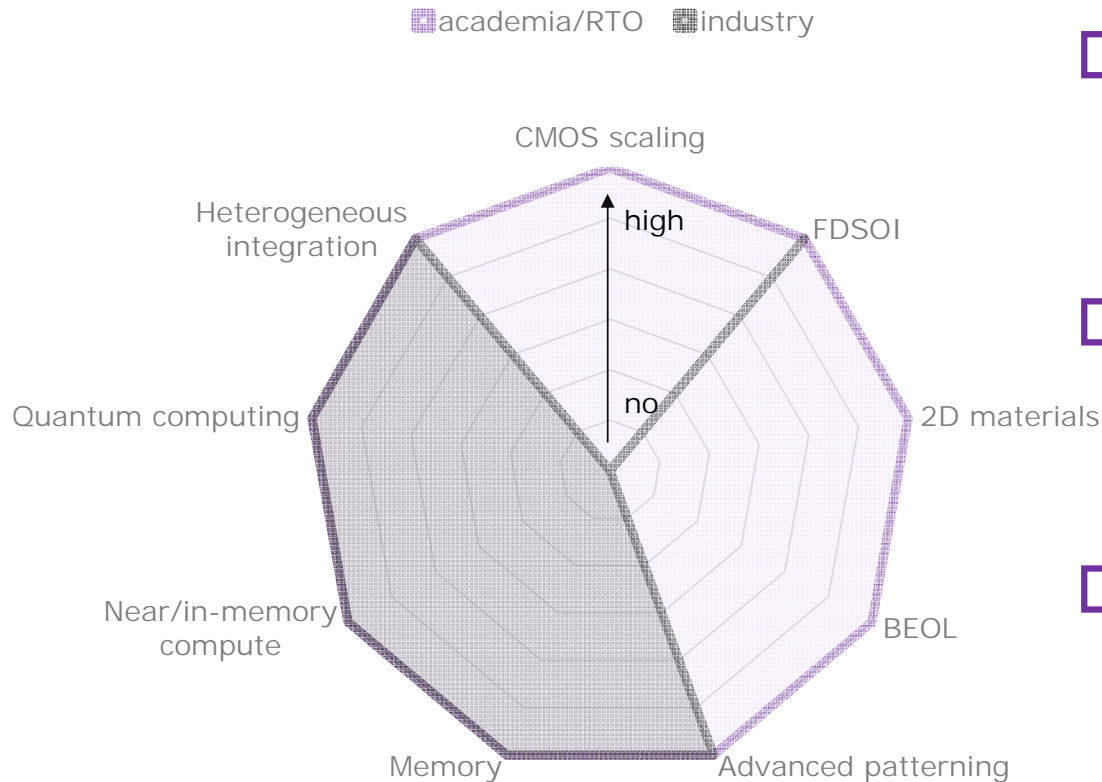
Device Backside Extension



Enhancing system performance by migrating system functions to the backside

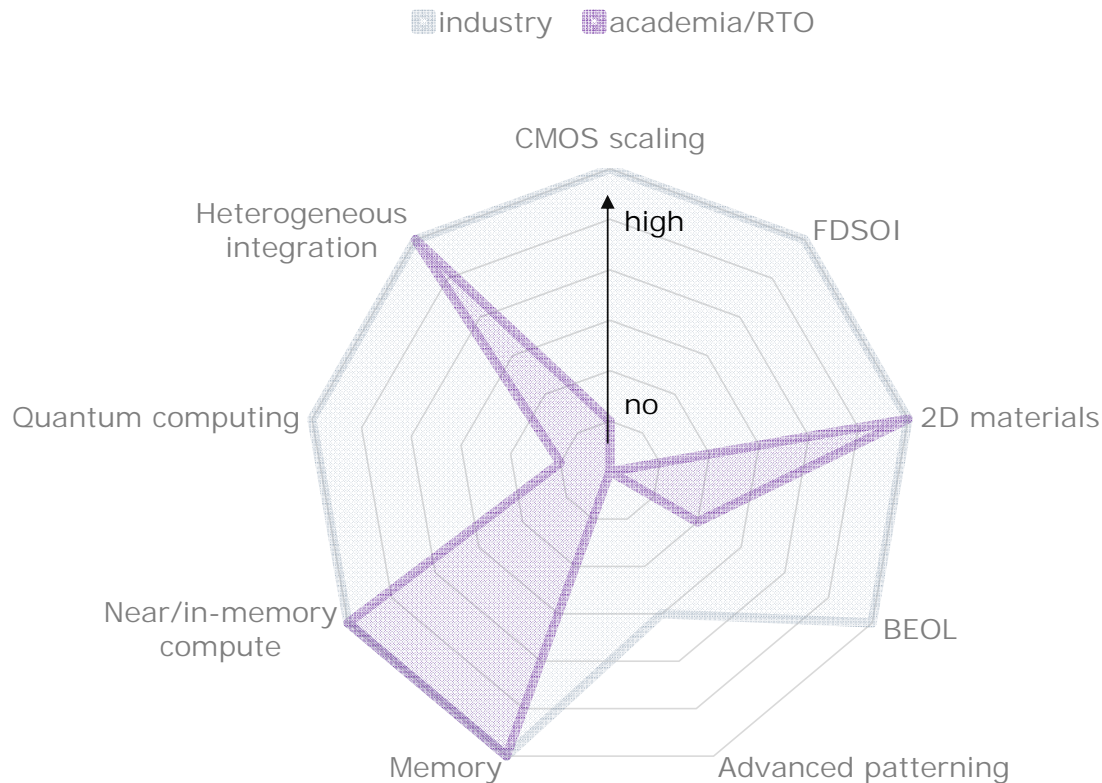
J. Ryckaert, ITF Japan 2022

EU and non-EU actors - EU



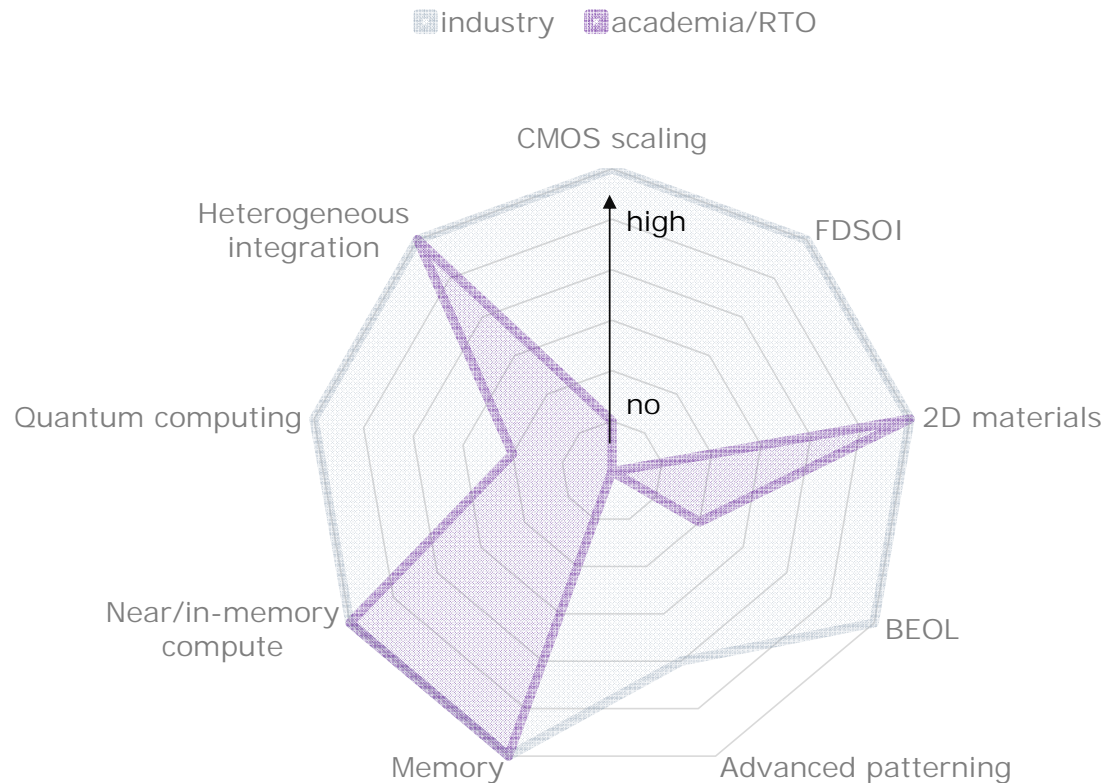
- R&D very strong in all areas of compute
- Unique strong position in EUV lithography
- In general, industrial EU players lacking to take up R&D

EU and non-EU actors - US



- Strong industrial activity in most areas of compute
- Weaker academic activity on traditional logic scaling
- Strong R&D in new materials, heterogeneous integration and memory

EU and non-EU actors - Asia



- Very similar to US
- Strong industrial activity in most areas of compute
- Weaker academic activity on traditional logic scaling
- Strong R&D in new materials, heterogeneous integration and memory

Summary

- ❑ Europe is very strong in R&D in all advanced compute areas
 - ❑ Manufacturing: starting to catch up- Intel and TSMC's initiatives in Germany
 - ❑ Lack of Fabless companies that drive the needs in terms of advanced compute
 - ❑ Strong initiatives in EU in start-up company creation. Maybe a solution?
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